



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Peter de Groot et al.

Art Unit : 2621

Serial No. : 09/769,859

Examiner : Unknown

Filed : January 25, 2001

Title : OPTICAL SYSTEMS FOR MEASURING FORM AND GEOMETRIC
DIMENSIONS OF PRECISION ENGINEERED PARTS

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Commissioner for Patents
Washington, D.C. 20231

APR 16 2003

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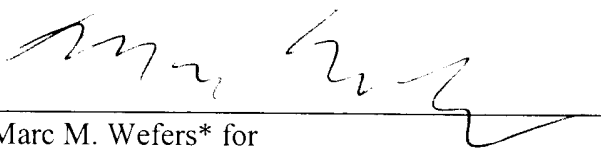
SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Copies of the references listed on the attached form PTO-1449 are enclosed.

This statement is being filed within three months of the filing date of the application or before the receipt of a first Office action on the merits. Please apply any charges or credits to Deposit Account No. 06-1050.

Respectfully submitted,

Date: 4/8/03


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***See attached document certifying that Marc M. Wefers has limited recognition to practice before the U.S. Patent and Trademark Office under 37 C.F.R. § 10.9(b).**

20616303.doc

CERTIFICATE OF MAILING BY FIRST CLASS MAIL

I hereby certify under 37 CFR §1.8(a) that this correspondence is being deposited with the United States Postal Service as first class mail with sufficient postage on the date indicated below and is addressed to the Commissioner for Patents, Washington, D.C. 20231.

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DAVID L. FEIGENBAUM
Typed or Printed Name of Person Signing Certificate

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Sheet 1 of 1Substitute Form PTO-1449
(Modified)U.S. Department of Commerce
Patent and Trademark OfficeAttorney's Docket No.
09712-057001Application No.
09/769,859**Information Disclosure Statement
by Applicant**

(Use several sheets if necessary)

(37 CFR §1.98(b))

Applicant
Peter de Groot et al.Filing Date
January 25, 2001Group Art Unit
2621**U.S. Patent Documents**

Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	6,271,925	8/7/2001	Muller	356	512	
	AB	6,100,977	8/8/2000	Muller	356	354	
	AC	5,502,564	3/26/1996	Ledger	356	355	
	AD						
	AE						
	AF						
	AG						
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	AI						
	AJ						
	AK						

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Foreign Patent Documents or Published Foreign Patent Applications

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	AL							
	AM							
	AN							
	AO							
	AP							

Other Documents (include Author, Title, Date, and Place of Publication)

Examiner Initial	Desig. ID	Document
	AQ	
	AR	
	AS	
	AT	

Examiner Signature

Date Considered

EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Substitute Disclosure Form (PTO-1449)

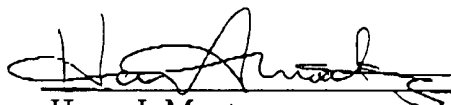
**BEFORE THE OFFICE OF ENROLLMENT AND DISCIPLINE
UNITED STATE PATENT AND TRADEMARK OFFICE**

LIMITED RECOGNITION UNDER 37 CFR § 10.9(b)

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This document constitutes proof of such recognition. The original of this document is on file in the Office of Enrollment and Discipline of the U.S. Patent and Trademark Office.

Expires: December 23, 2003



Harry I. Moatz
Director of Enrollment and Discipline